Product data sheet

1. General description

Planar passivated high commutation three quadrant triac in a SOT78D (TO-220AB) internally insulated plastic package. This "series BT" triac will commutate the full RMS current at the maximum rated junction temperature ($T_{j(max)} = 150$ °C) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

2. Features and benefits

- 3Q technology for improved noise immunity
- High commutation capability with maximum false trigger immunity
- High immunity to false turn-on by dV/dt
- High T_{i(max)}
- Isolated mounting base with 2500 V (RMS) isolation
- Least sensitive gate for highest noise immunity
- Planar passivated for voltage ruggedness and reliability
- Triggering in three quadrants only

3. Applications

- Electronic thermostats (heating and cooling)
- Motor controls
- · Rectifier-fed DC inductive loads e.g. DC motors and solenoids

4. Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
|------------------------|--|---|--|-----|-----|-----|------|
| V_{DRM} | repetitive peak off- state voltage | | | - | - | 800 | V |
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_{mb} \le 120 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3 | | - | - | 10 | Α |
| I _{TSM} | non-repetitive peak on- state current | full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig. 4; Fig. 5 | | - | - | 100 | Α |
| | | full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms | | - | - | 110 | Α |
| T _j | junction temperature | | | - | - | 150 | °C |
| Static characteristics | | | | | | | |
| I _{GT} | gate trigger current | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$ | | 2 | - | 50 | mA |

| Symbol | Parameter | Conditions | | Min | Тур | Max | Unit |
|---------------------|-----------------------------------|---|--|------|-----|-----|------|
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$ | | 2 | - | 50 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \frac{\text{Fig. 7}}{}$ | | 2 | - | 50 | mA |
| V _T | on-state voltage | I _T = 15 A; T _j = 25 °C; <u>Fig. 10</u> | | - | 1.3 | 1.6 | V |
| Dynamic char | Dynamic characteristics | | | | | | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | | 1000 | - | - | V/µs |

5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-------------------------|--|----------------|
| 1 | T1 | main terminal 1 | mb | T2——T1 |
| 2 | T2 | main terminal 2 | } | G sym051 |
| 3 | G | gate | | Symoor |
| mb | n.c. | mounting base; isolated | | |
| | | | \\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\ | |
| | | | | |
| | | | TO-220AB (SOT78D) | |

6. Ordering information

Table 3. Ordering information

| Type number | Package | | | | |
|---------------|----------|---|---------|--|--|
| | Name | Description | Version | | |
| BTA410Y-800BT | TO-220AB | plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 | SOT78D | | |

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---------------------|--|--|-----|-----|------|
| V_{DRM} | repetitive peak off-state voltage | | - | 800 | V |
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_{mb} \le 120 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3 | - | 10 | Α |
| I _{TSM} | non-repetitive peak on- state current | full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5 | - | 100 | Α |
| | | full sine wave; T _{j(init)} = 25 °C; t _p = 16.7 ms | - | 110 | Α |
| I ² t | I ² t for fusing | t _p = 10 ms; sine-wave pulse | - | 50 | A²s |
| dl _T /dt | rate of rise of on-state current | I _G = 0.2 A | - | 100 | A/µs |
| I _{GM} | peak gate current | | - | 2 | Α |
| P _{GM} | peak gate power | | - | 5 | W |
| $P_{G(AV)}$ | average gate power | over any 20 ms period | - | 0.5 | W |
| T _{stg} | storage temperature | | -40 | 150 | °C |
| T _j | junction temperature | | - | 150 | °C |

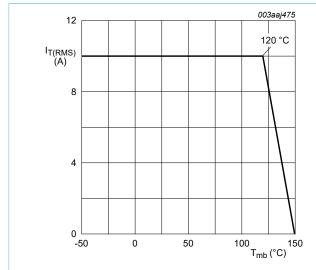


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

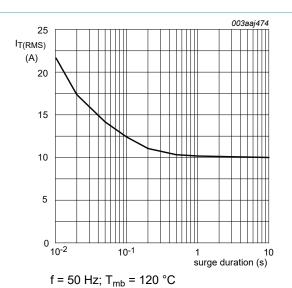


Fig. 2. RMS on-state current as a function of surge duration; maximum values

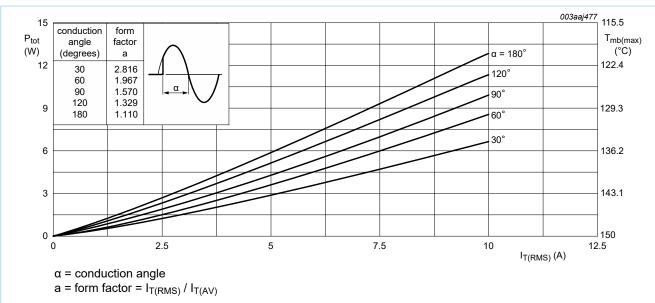


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

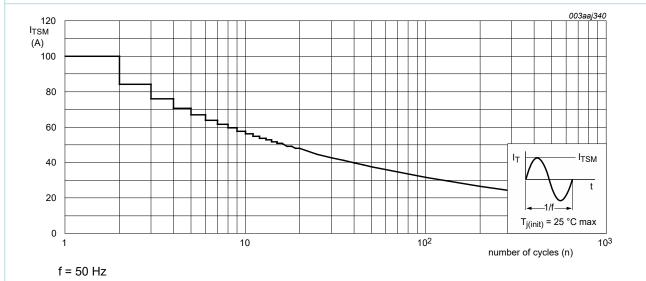
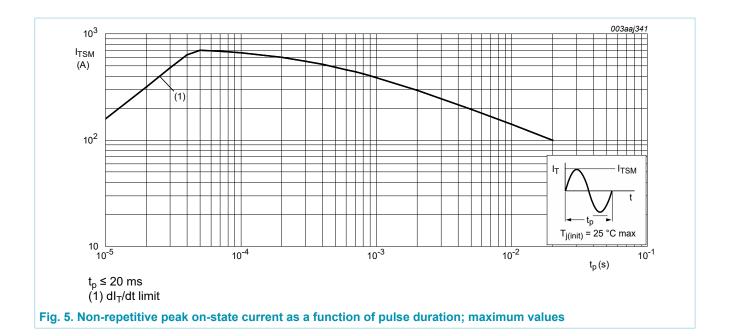


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

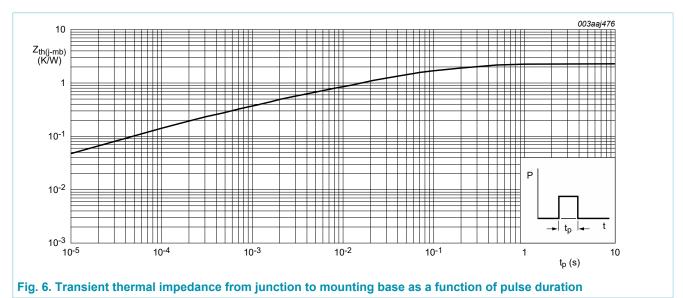


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8. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|--|--------------------|-----|-----|-----|------|
| R _{th(j-mb)} | thermal resistance from junction to mounting base | full cycle; Fig. 6 | - | - | 2.3 | K/W |
| R _{th(j-a)} | thermal resistance from junction to ambient free air | in free air | - | 60 | - | K/W |



9. Isolation characteristics

Table 6. Isolation characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|------------------------|-----------------------|---|-----|-----|------|------|
| V _{isol(RMS)} | RMS isolation voltage | from all terminals to external heatsink; sinusoidal waveform; clean and dust free; $50~Hz \le f \le 60~Hz$; $RH \le 65~\%$; $T_{mb} = 25~^{\circ}C$ | - | - | 2500 | V |
| C _{isol} | isolation capacitance | from main terminal 2 to external heatsink; f = 1 MHz; T _{mb} = 25 °C | - | 10 | - | pF |

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10. Characteristics

Table 7. Characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|--|------|-----|-----|------|
| Static char | acteristics | | , | | | , |
| I _{GT} | gate trigger current | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$ | 2 | - | 50 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 ^{\circ}\text{C}; \underline{\text{Fig. 7}}$ | 2 | - | 50 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{G-};$ $T_j = 25 \text{ °C}; \underline{\text{Fig. 7}}$ | 2 | - | 50 | mA |
| L | latching current | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 8$ | - | - | 60 | mA |
| | | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 8$ | - | - | 90 | mA |
| | | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 ^{\circ}\text{C}; \text{ Fig. 8}$ | - | - | 60 | mA |
| l _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u> | - | - | 60 | mA |
| V _T | on-state voltage | I _T = 15 A; T _j = 25 °C; <u>Fig. 10</u> | - | 1.3 | 1.6 | V |
| V _{GT} | gate trigger voltage | V _D = 12 V; T _j = 25 °C; <u>Fig. 11</u> | - | 8.0 | 1 | V |
| | | V _D = 400 V; T _j = 150 °C; <u>Fig. 11</u> | 0.25 | 0.4 | - | V |
| I _D | off-state current | V _D = 800 V; T _j = 150 °C | - | 0.4 | 2 | mA |
| Dynamic cl | naracteristics | | | | | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 536 V; T_j = 150 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 1000 | - | - | V/µs |
| dI _{com} /dt | rate of change of commutating current | V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 10 A; dV_{com}/dt = 20 V/µs; (snubberless condition); gate open circuit | 20 | - | - | A/ms |
| | | V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 10 A; dV_{com}/dt = 10 V/µs; gate open circuit | 28 | - | - | A/ms |
| | | $V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 10 \text{ A};$ $dV_{com}/dt = 1 \text{ V/}\mu\text{s}; gate open circuit}$ | 45 | - | - | A/ms |

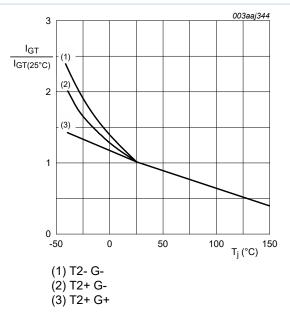


Fig. 7. Normalized gate trigger current as a function of junction temperature

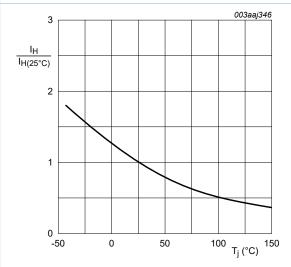


Fig. 9. Normalized holding current as a function of junction temperature

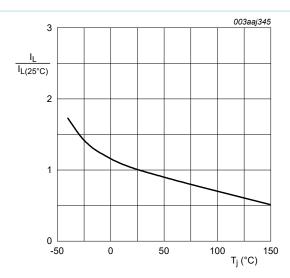
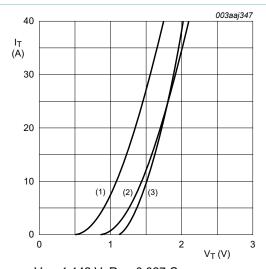
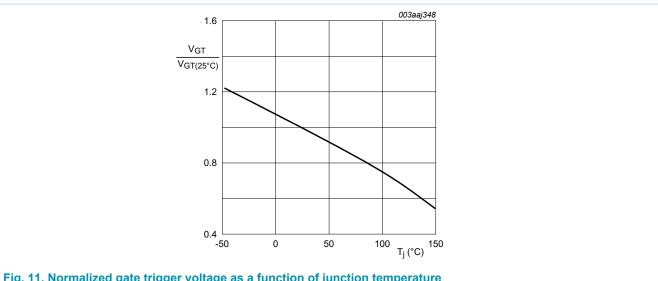


Fig. 8. Normalized latching current as a function of junction temperature



 V_o = 1.142 V; R_s = 0.027 Ω (1) T_j = 150 °C; typical values (2) T_j = 150 °C; maximum values (3) T_j = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage



11. Package outline

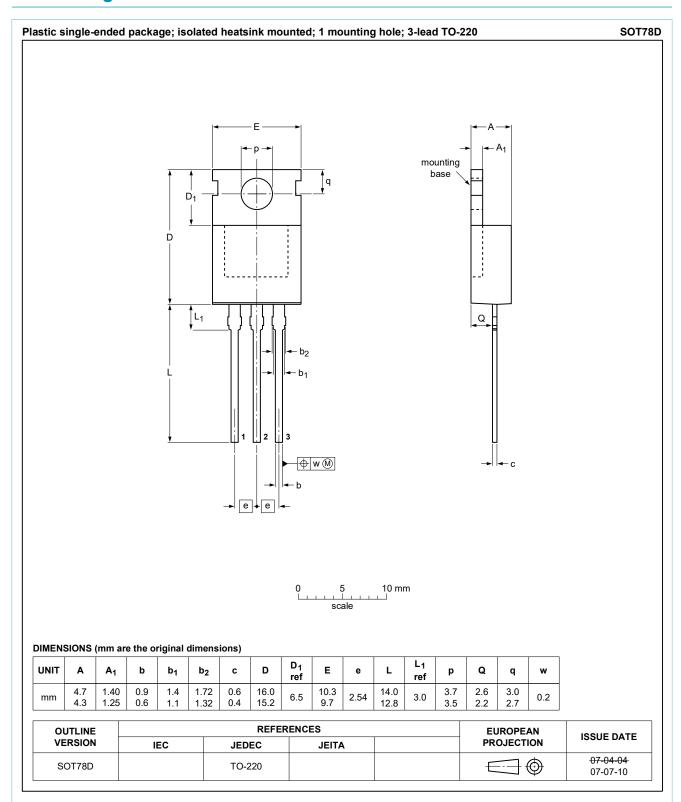


Fig. 12. Package outline TO-220AB (SOT78D)

12. Legal information

Data sheet status

| Document status [1][2] | Product status [3] | Definition |
|--------------------------------------|--------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
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